

INTERNATIONAL STANDARD



**Organic light emitting diode (OLED) displays –
Part 6-2: Measuring methods of visual quality and ambient performance**



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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
Fax: +41 22 919 03 00
info@iec.ch
www.iec.ch

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Part 6-2: Measuring methods of visual quality and ambient performance**

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ORGANIC LIGHT EMITTING DIODE (OLED) DISPLAYS –

Part 6-2: Measuring methods of visual quality and ambient performance

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International Standard IEC 62341-6-2 has been prepared by IEC technical committee 110: Electronic display devices.

This second edition cancels and replaces the first edition published in 2012. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) Contents of 7.4 are changed.
- b) Contents and items of Annex C are changed.
- c) Annex B is added.

The text of this standard is based on the following documents:

FDIS	Report on voting
110/695/FDIS	110/718/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all parts of the IEC 62341 series, published under the general title *Organic light emitting diode (OLED) displays*, can be found on the IEC website.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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- replaced by a revised edition, or
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ORGANIC LIGHT EMITTING DIODE (OLED) DISPLAYS –

Part 6-2: Measuring methods of visual quality and ambient performance

1 Scope

This part of IEC 62341 specifies the standard measurement conditions and measurement methods for determining the visual quality and ambient performance of organic light emitting diode (OLED) display modules and panels. This document mainly applies to colour display modules.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at www.electropedia.org)

IEC 61966-2-1, *Multimedia systems and equipment – Colour measurement and management – Part 2-1: Colour management – Default RGB colour space – sRGB*

IEC 62341-1-2, *Organic light emitting diode (OLED) displays – Part 1-2: Terminology and letter symbols*

CIE 15:2004, *Colorimetry*

3 Terms, definitions and abbreviations

3.1 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60050-845 and IEC 62341-1-2, as well as the following apply.

3.1.1

visual inspection

means for checking image quality by human visual observation for classification and comparison against limit sample criteria

3.1.2

subpixel defects

all or part of a single subpixel, the minimum colour element, which is visibly brighter or darker than surrounding subpixels of the same colour.

Note 1 to entry: Further classifications of subpixel defects are made depending on the number and configuration of multiple subpixel defects within a region of the display.

Note 2 to entry: For monochromatic displays, the term “dot defect” may be used.